



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Art Unit: 2815  
Examiner: Mr. Joseph H. Nguyen

In re PATENT APPLICATION of:

Applicant : Takashi NOGUCHI )  
Serial No. : 10/822,691 )  
Filed : April 13, 2004 )  
For : HEAT RADIATION )  
STRUCTURE OF )  
SEMICONDUCTOR DEVICE, )  
AND MANUFACTURING )  
METHOD THEREOF )  
Attorney Ref. : OKI 419 )

**INFORMATION  
DISCLOSURE  
STATEMENT**

September 22, 2005

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This is an Information Disclosure Statement submitted under 37 CFR 1.97-1.98,  
within the time period specified in 37 CFR 1.97(c).

A Form PTO-1449 and a copy of the reference cited therein are attached. Since the  
reference is written in the Japanese language, an English language translation is also attached  
to show the relevance of the reference.

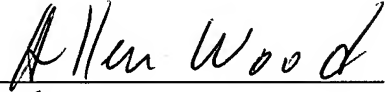
Pursuant to 37 CFR 1.97(c), the \$180 fee set forth in 37 CFR 1.17(p) is being  
submitted concurrently.

| 09/23/2005 SZEWDIE1 00000150 10822691  
| 02 FC:1806 180.00 0P

FEE ENCLOSED: \$300  
Please charge any further  
fee to our Deposit Account  
No. 18-0002

In view of the foregoing, it is respectfully requested that the reference be considered and made of record.

Respectfully submitted,

A handwritten signature in cursive script that reads "Allen Wood". The signature is written in dark ink and is positioned above a horizontal line.

Allen Wood

Registration No. 28,134

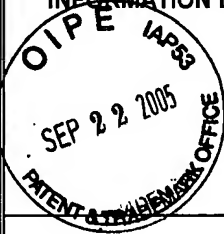
RABIN & BERDO, PC

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AW/rw

<b>FORM PTO-1449</b>  <b>INFORMATION DISCLOSURE STATEMENT</b>				Atty Docket  <div style="text-align: center;"><b>OKI 419</b></div>		Application No.  <div style="text-align: center;"><b>10/822,691</b></div>	
				Applicant  <div style="text-align: center;"><b>Takashi NOGUCHI</b></div>			
				Filing Date <div style="text-align: center;">April 13, 2004</div>		Group Unit <div style="text-align: center;">2815</div>	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
<b>FOREIGN PATENT DOCUMENTS</b>							
		Document Number	Date	Country	Class	Sub- Class	Trans- lation
	AI	2003-51572	02/2003	Japan			YES
	AJ						
	AK						
	AL						
	AM						
	AN						
	AO						
<b>OTHER (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AP						
	AQ						
	AR						
Examiner					Date Considered		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							